

<IGBT Modules>

## **CM600DY-13T**

HIGH POWER SWITCHING USE INSULATED TYPE



dual switch (half-bridge)

Collector current I<sub>C</sub> ...... 6 0 0 A

Collector-emitter voltage V<sub>CES</sub> ...... 6 5 0 V

Maximum junction temperature T<sub>vjmax</sub> ....... 1 7 5 °C

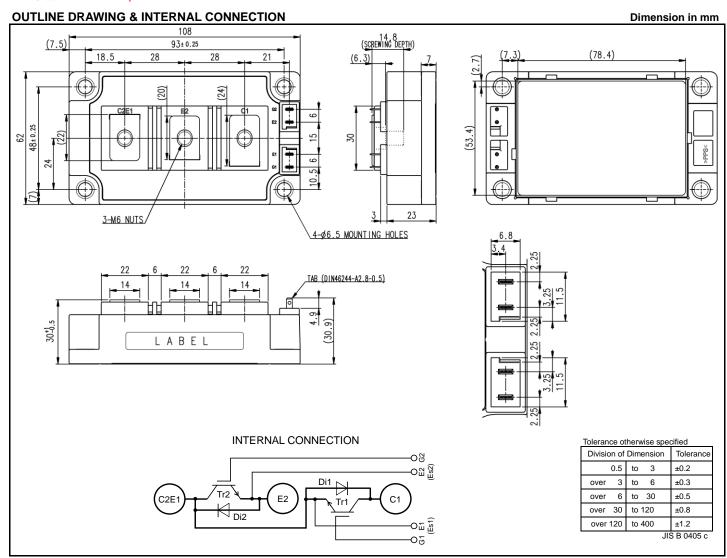
- •Flat base type
- Copper base plate (Nickel-plating)
- Nickel-plating tab terminals
- •RoHS Directive compliant
- •UL Recognized under UL1557, File No.E323585

#### **APPLICATION**

AC Motor Control, Motion/Servo Control, Power supply, etc.

**OPTION** (Below options are available.)

- $\bullet \text{PC-TIM} \ (\underline{P} \text{hase} \ \underline{C} \text{hange} \ \underline{T} \text{hermal} \ \underline{I} \text{nterface} \ \underline{M} \text{aterial}) \ \text{pre-apply}$
- •V<sub>CEsat</sub> selection for parallel connection



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## HIGH POWER SWITCHING USE

### INSULATED TYPE

## MAXIMUM RATINGS ( $T_{vj}$ =25 °C, unless otherwise specified)

Symbol	Item	Conditions	Rating	Unit	
V <sub>CES</sub>	Collector-emitter voltage	G-E short-circuited	650	V	
V <sub>GES</sub>	Gate-emitter voltage	C-E short-circuited	± 20	V	
Ic	Collector ourment	DC, T <sub>C</sub> =139 °C* (Note2, 4)	600	^	
I <sub>CRM</sub>	Collector current	Pulse, Repetitive (Note3)	1200	A	
P <sub>tot</sub>	Total power dissipation	T <sub>C</sub> =25 °C (Note2, 4)	4165	W	
I <sub>E</sub> (Note1)	Facilities assumed	DC (Note2)	600	^	
I <sub>ERM</sub> (Note1)	Emitter current	Pulse, Repetitive (Note3)	1200	A	
V <sub>isol</sub>	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	4000	V	
T <sub>vjmax</sub>	Maximum junction temperature	Instantaneous event (overload)	175	°C	
$T_{Cmax}$	Maximum case temperature	(Note4)	150*		
T <sub>vjop</sub>	Operating junction temperature	Continuous operation (under switching)	-40 ~ +150	°C	
T <sub>stg</sub>	Storage temperature	-	-40 ~ +150*		

### ELECTRICAL CHARACTERISTICS (Tvj=25 °C, unless otherwise specified)

Cumbal	ltom	Conditions			Limits		l lait
Symbol Item		Conditions	Conditions		Тур.	Max.	Unit
I <sub>CES</sub>	Collector-emitter cut-off current	V <sub>CE</sub> =V <sub>CES</sub> , G-E short-circuited		-	=	1.0	mA
I <sub>GES</sub>	Gate-emitter leakage current	V <sub>GE</sub> =V <sub>GES</sub> , C-E short-circuited	V <sub>GE</sub> =V <sub>GES</sub> , C-E short-circuited		-	0.5	μΑ
V <sub>GE(th)</sub>	Gate-emitter threshold voltage	I <sub>C</sub> =60 mA, V <sub>CE</sub> =10 V	I <sub>C</sub> =60 mA, V <sub>CE</sub> =10 V		6.0	6.6	V
		I <sub>C</sub> =600 A, V <sub>GE</sub> =15 V,	T <sub>vj</sub> =25 °C	-	1.45	1.75	V
V <sub>CEsat</sub>		Refer to the figure of test circuit	T <sub>vj</sub> =125 °C	-	1.55	-	
(Terminal)	Only of an arrive and arrive the arrive to	(Note5)	T <sub>vj</sub> =150 °C	-	1.60	-	
	Collector-emitter saturation voltage	I <sub>C</sub> =600 A,	T <sub>vj</sub> =25 °C	-	1.30	1.55	
V <sub>CEsat</sub>		V <sub>GE</sub> =15 V,	T <sub>vj</sub> =125 °C	-	1.35	-	V
(Chip)		(Note5)	T <sub>vj</sub> =150 °C	-	1.35	-	1
Cies	Input capacitance			-	-	80.2	
Coes	Output capacitance	V <sub>CE</sub> =10 V, G-E short-circuited		-	-	3.4	nF
Cres	Reverse transfer capacitance		-	-	1.5		
Q <sub>G</sub>	Gate charge	V <sub>CC</sub> =300 V, I <sub>C</sub> =600 A, V <sub>GE</sub> =15 V		-	2.48	-	μC
t <sub>d(on)</sub>	Turn-on delay time	V 000 V I 000 A V 45 V	-	-	400	- ns	
tr	Rise time	Vcc=300 V, Ic=600 A, V <sub>GE</sub> =±15 V,		-	-		200
t <sub>d(off)</sub>	Turn-off delay time			-	-		500
t <sub>f</sub>	Fall time	$=$ R <sub>G</sub> =1.0 $\Omega$ , inductive load	R <sub>G</sub> =1.0 Ω, Inductive load		-	400	1
		I <sub>E</sub> =600 A, G-E short-circuited,	T <sub>vj</sub> =25 °C	-	2.10	2.90	V
V <sub>EC</sub> (Note.1)		Refer to the figure of test circuit	T <sub>vj</sub> =125 °C	-	2.05	-	
(Terminal)		(Note5)	T <sub>vj</sub> =150 °C	-	2.05	-	1
	Emitter-collector voltage	I <sub>E</sub> =600 A,	T <sub>vj</sub> =25 °C	-	1.90	2.65	
V <sub>EC</sub> (Note.1)		G-E short-circuited,	T <sub>vj</sub> =125 °C	-	1.80	-	V
(Chip)		(Note5)	T <sub>vj</sub> =150 °C	-	1.80	-	1
t <sub>rr</sub> (Note1)	Reverse recovery time	V <sub>CC</sub> =300 V, I <sub>E</sub> =600 A, V <sub>GE</sub> =±15 V,	1	-	-	250	ns
Q <sub>rr</sub> (Note1)	Reverse recovery charge	$R_G=1.0 \Omega$ , Inductive load		-	21	-	μC
Eon	Turn-on switching energy per pulse	V <sub>CC</sub> =300 V, I <sub>C</sub> =I <sub>E</sub> =600 A,		-	8.8	-	
E <sub>off</sub>	Turn-off switching energy per pulse	$V_{GE}$ =±15 V, R <sub>G</sub> =1.0 $\Omega$ , T <sub>vj</sub> =150 °C,		-	33.2	-	mJ
E <sub>rr</sub> (Note1)	Reverse recovery energy per pulse	Inductive load		-	12.2	-	mJ
R <sub>CC'+EE'</sub>	Internal lead resistance	Main terminals-chip, per switch, T <sub>C</sub> =25 °C (Note4)		-	0.3	-	mΩ
r <sub>g</sub>	Internal gate resistance	Per switch		-	1.0	-	Ω

<sup>\*:</sup> The value of PC-TIM applied module is limited by the heat resistant temperature of PC-TIM.

### HIGH POWER SWITCHING USE

### INSULATED TYPE

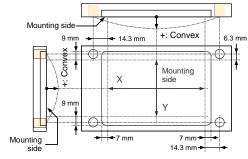
### THERMAL RESISTANCE CHARACTERISTICS

Symbol	Item	Conditions	Limits			Unit
	item	Conditions	Min.	Тур.	Max.	Offit
$R_{th(j-c)Q}$	Thermal resistance	Junction to case, per Inverter IGBT (Note4)	-	-	36	K/kW
$R_{th(j-c)D}$	Thermairesistance	Junction to case, per Inverter FWD (Note4)	-	=	56	N/KVV
R <sub>th(c-s)</sub>	Contact thermal resistance	Case to heat sink, per 1 module  Thermal grease applied (Note4, 6)	-	13.3	-	K/kW

### **MECHANICAL CHARACTERISTICS**

Symbol	ltom	Conditions			Unit		
	Item	Conditions		Min.	Тур.	Max.	Onit
Mt	Mounting torque	Main terminals	M 6 screw	3.5	4.0	4.5	N∙m
Ms	Mounting torque	Mounting to heat sink	M 6 screw	3.5	4.0	4.5	N∙m
ds	Constant distant	Terminal to terminal		17.3	-	-	- mm
	Creepage distance	Terminal to base plate		25.3	=	-	
da	Classes	Terminal to terminal		12.6	-	-	mm mm
	Clearance	Terminal to base plate		21.8	-	-	
ес	Flatness of base plate	On the centerline X, Y (Note7)		±0	=	+200	μm
m	mass	-		-	260	-	g

- \*: This product is compliant with the Restriction of the Use of Certain Hazardous Substances in Electrical and Electronic Equipment (RoHS) directive 2011/65/EU.
- Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free-wheeling diode (FWD).
  - 2. Junction temperature  $(T_{\nu j})$  should not increase beyond  $T_{\nu j\,m\,a\,x}$  rating.
  - 3. Pulse width and repetition rate should be such that the device junction temperature (T<sub>vj</sub>) dose not exceed T<sub>vjmax</sub> rating.
  - 4. Case temperature (T<sub>C</sub>) and heat sink temperature (T<sub>S</sub>) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.
  - 5. Pulse width and repetition rate should be such as to cause negligible temperature rise. Refer to the figure of test circuit.
  - 6. Typical value is measured by using thermally conductive grease of  $\lambda$ =3.0 W/(m·K)/D<sub>(C-S)</sub>=50  $\mu$ m.
  - 7. The base plate (mounting side) flatness measurement points (X, Y) are shown in the following figure.



HIGH POWER SWITCHING USE

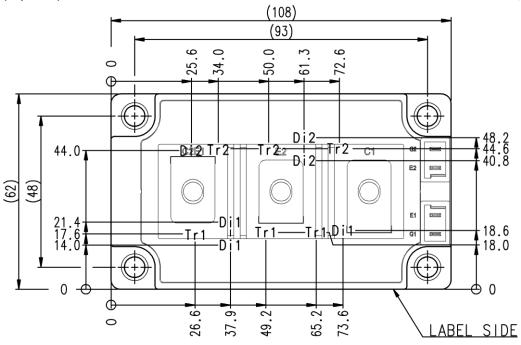
INSULATED TYPE

### **RECOMMENDED OPERATING CONDITIONS**

Symbol	Item	Conditions	Limits			Unit
	item		Min.	Тур.	Max.	Offic
V <sub>cc</sub>	(DC) Supply voltage	Applied across C1-E2 terminals	-	300	450	V
$V_{GEon}$	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2 terminals	13.5	15.0	16.5	V
R <sub>G</sub>	External gate resistance	Per switch	1.0	-	10	Ω

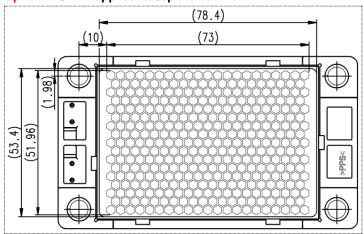
### **CHIP LOCATION (Top view)**

Dimension in mm, tolerance: ±1 mm

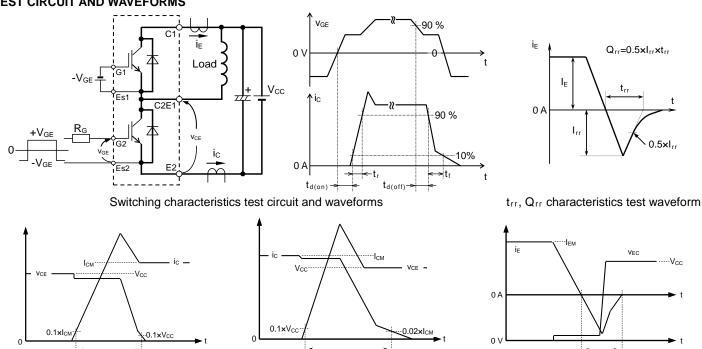


Tr1/Tr2: IGBT, Di1/Di2: FWD

## **Option: PC-TIM applied baseplate outline**



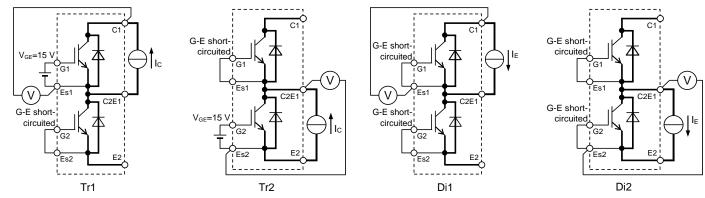
### **TEST CIRCUIT AND WAVEFORMS**



IGBT Turn-off switching energy Turn-on / Turn-off switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

### **TEST CIRCUIT**

IGBT Turn-on switching energy



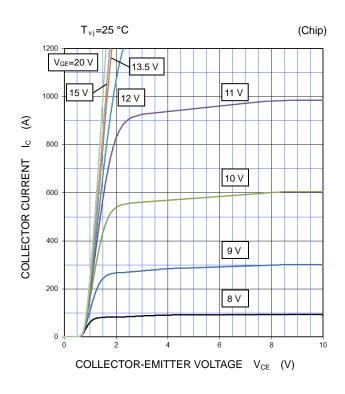
V<sub>CEsat</sub> characteristics test circuit

V<sub>EC</sub> characteristics test circuit

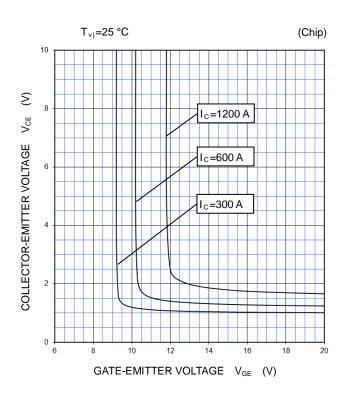
FWD Reverse recovery energy

### **PERFORMANCE CURVES**

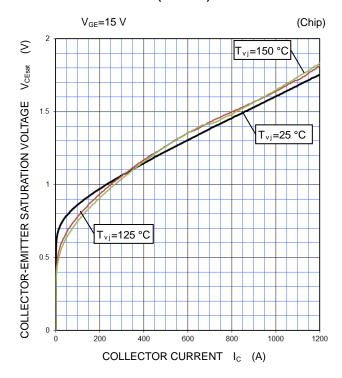
## OUTPUT CHARACTERISTICS (TYPICAL)



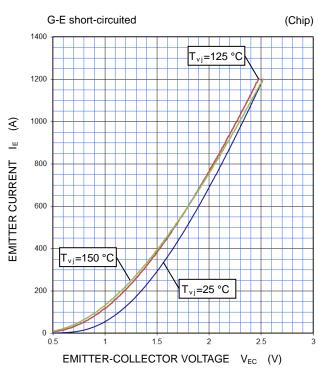
## COLLECTOR-EMITTER VOLTAGE CHARACTERISTICS (TYPICAL)



#### COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)



#### FREE WHEELING DIODE FORWARD CHARACTERISTICS (TYPICAL)

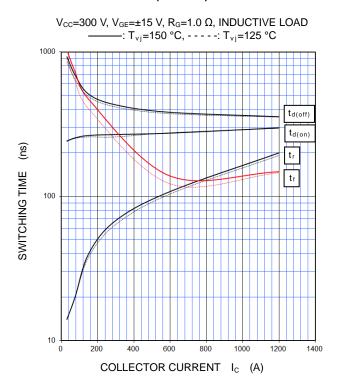


HIGH POWER SWITCHING USE

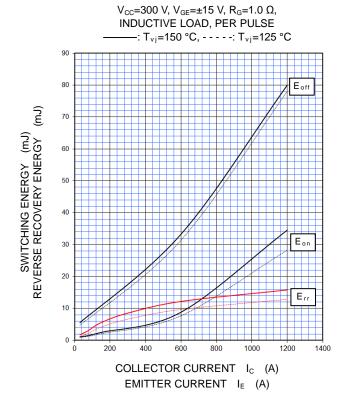
### **INSULATED TYPE**

### **PERFORMANCE CURVES**

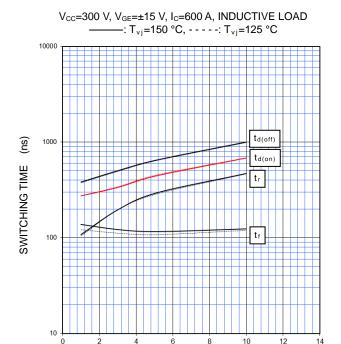
## HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



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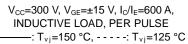


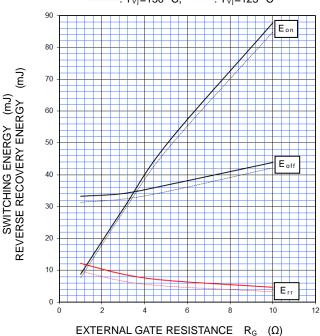
## HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



## HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

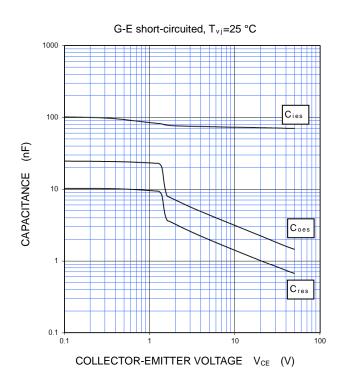
EXTERNAL GATE RESISTANCE R<sub>G</sub>



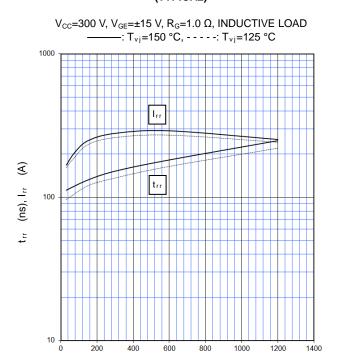


### **PERFORMANCE CURVES**

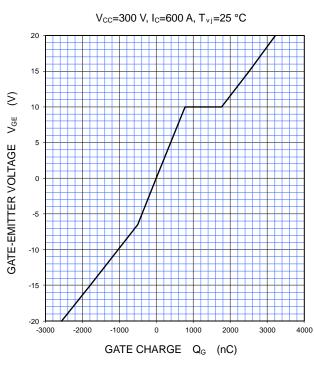
## CAPACITANCE CHARACTERISTICS (TYPICAL)



# FREE WHEELING DIODE REVERSE RECOVERY CHARACTERISTICS (TYPICAL)



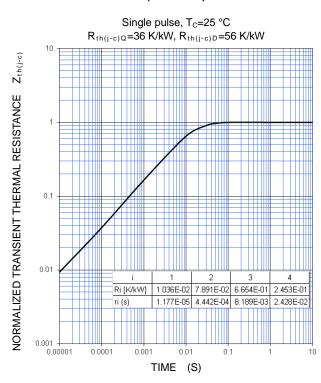
## GATE CHARGE CHARACTERISTICS (TYPICAL)



## TRANSIENT THERMAL IMPEDANCE CHARACTERISTICS (MAXIMUM)

 $I_E$  (A)

EMITTER CURRENT



Note: The characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

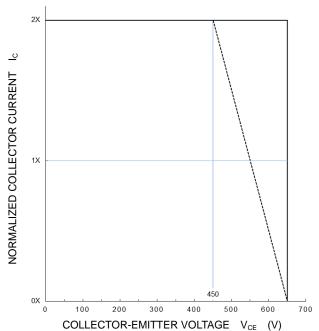
HIGH POWER SWITCHING USE

INSULATED TYPE

### **PERFORMANCE CURVES**

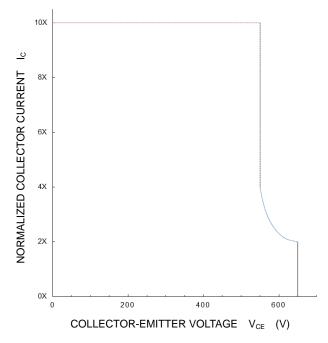
#### TURN-OFF SWITCHING SAFE OPERATING AREA (REVERSE BIAS SAFE OPERATING AREA) (MAXIMUM)

 $V_{CC}$ ≤450 V,  $V_{GE}$ =±15 V,  $R_{G}$ =1.0~10  $\Omega$ ,
——:  $T_{v_j}$ =25~150 °C (Normal load operations (Continuous)
----:  $T_{v_j}$ =175 °C (Unusual load operations (Limited period)



## SHORT-CIRCUIT SAFE OPERATING AREA (MAXIMUM)

 $V_{CC}{\le}400$  V,  $V_{GE}{=}{\pm}15$  V,  $R_{G}{=}1.0{\sim}10$   $\Omega,$   $T_{vj}{=}$  25  ${\sim}$  150 °C,  $t_W{\le}8$   $\mu s,$  Non-Repetitive



HIGH POWER SWITCHING USE

**INSULATED TYPE** 

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Publication Date : May 2018 CMH-11284-B